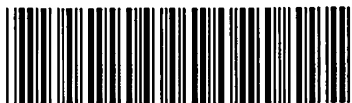


Search Notes

Application/Control No.

10/510,254

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

DEKKERS ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	258	1/4/2006	HN
330	295	1/3/2006	HN
330	252	1/3/2006	HN
330	253	1/4/2006	HN
330	84	1/4/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
US-PGPUB		7/3/2006	HN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	1/4/2006	HN
EAST UPDATE SEARCH	7/3/2006	HN